

Notice of Allowability	Application No.:	Applicant(s)	
	09/944,648	DINAN ET AL.	
	Examiner	Art Unit	
	Tianjie Chen	2627	

-- **The MAILING DATE of this communication appears on the cover sheet with the correspondence address--**

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. This communication is responsive to RCE filed on 09/16/2006.
2. The allowed claim(s) is/are 1-10, 19-24.
3. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) All
 - b) Some*
 - c) None
 1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) hereto or 2) to Paper No./Mail Date _____.
 - (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. Notice of References Cited (PTO-892)
2. Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. Information Disclosure Statements (PTO/SB/08),
Paper No./Mail Date _____
4. Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. Notice of Informal Patent Application
6. Interview Summary (PTO-413),
Paper No./Mail Date _____.
7. Examiner's Amendment/Comment
8. Examiner's Statement of Reasons for Allowance
9. Other _____.

Chen Tianjie
TIANJIE CHEN
PRIMARY EXAMINER

DETAILED ACTION

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 02/16/2005 has been entered.

Examiner's Amendment

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Robert O. Guillot on 11/20/2006.

The application has been amended as follows:

- In claim 1, lines 6-9 have been replaced by -- a P2 pole tip fabricated upon of the write gap layer, wherein the P2 pole tip consists of a first sidewall portion, which is formed from a seed layer, and a second portion, which is composed of a pole tip material, and wherein the P2 pole tip has a thickness dimension t, and a base having a width dimension W;--.
- In claim 2, line 2; "non-seed layer" has been changed to --pole tip--.
- In claim 2, line 2; "sidewall" has been deleted.
- In claim 3, line 4; "non-seed layer" has been changed to --pole tip--.
- In claim 4, line 2; "non-seed layer" has been changed to --pole tip--.

- In claim 5, line 2; “non-seed layer” has been changed to --pole tip--.
- In claim 6, lines 9-12 has been replaced by -- a P2 pole tip fabricated upon of the write gap layer, wherein the P2 pole tip consists of a first sidewall portion, which is formed from a seed layer, and a second portion, which is composed of a pole tip material, and wherein the P2 pole tip has a thickness dimension t, and a base having a width dimension W;--.
- In claim 7, line 2; “non-seed layer” has been changed to --pole tip--.
- In claim 7, line 2; “sidewall” has been deleted.
- In claim 8, line 4; “non-seed layer” has been changed to --pole tip--.
- In claim 9, line 2; “non-seed layer” has been changed to --pole tip--.
- In claim 10, line 2; “non-seed layer” has been changed to --pole tip--.
- In claim 19, line 11; “non-seed layer” has been changed to --pole tip--.
- In claim 21, line 2; “non-seed layer” has been changed to --pole tip--.
- In claim 22, line 3; “non-seed layer” has been changed to --pole tip--.
- In claim 23, line 2; “non-seed layer” has been changed to --pole tip--.
- In claim 24, line 2; “non-seed layer” has been changed to --pole tip--.

3. The following is an examiner’s statement of reasons for allowance:

- With regard to independent claims 1 and 6; as the closest reference, Ohtsuka et al (US 5,774,308) discloses a magnetic head including: a substrate; a read head being fabricated upon the substrate; a P1 pole being fabricated upon the read head; a write gap layer being fabricated upon the P1 pole; a P2 pole tip fabricated upon of the write gap layer, wherein the P2 pole tip has a thickness dimension t, and a base having a width dimension W; and wherein the seed layer is comprised of an integrally formed layer of seed layer material that forms

the base of the P2 pole tip and the first sidewall portion of the P2 pole tip that extends throughout the thickness t of the P2 pole tip; **but fails to show** a P2 pole tip consists of a first sidewall portion, which is formed from a seed layer, and a second portion, which is composed of a pole tip material.

- With regard to independent claim 19; as the closest reference, Ohtsuka et al (US 5,774,308) discloses a magnetic head including: a substrate; a read head being fabricated upon the substrate; a P1 pole being fabricated upon the read head; a write gap layer being fabricated upon the P1 pole; a P2 pole tip being fabricated upon portions of the write gap layer, wherein the P2 pole tip includes a base surface that is disposed upon the write gap layer and a first sidewall surface layer that is disposed generally perpendicularly to the base surface, and wherein the base surface layer and the first sidewall surface layer are comprised of an integrally formed layer of P2 pole tip seed layer material and wherein the P2 pole tip includes a pole tip layer material portion, and wherein the P2 pole tip includes a second sidewall surface layer that is disposed opposite to the first sidewall surface layer; **but fails to show** that the second layer is comprised of the pole tip layer material.
- Applicant asserts “the magnetic head of the present invention that it includes a P2 pole tip having a narrow width” (Specification, p. 3)

4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled “Comments on Statement of Reasons for Allowance.”

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tianjie Chen whose telephone number is 571-272-7570. The examiner can normally be reached on 8:00-4:30, Mon-Fri.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Hoa Nguyen can be reached on 571-272-7579. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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PRIMARY EXAMINER